

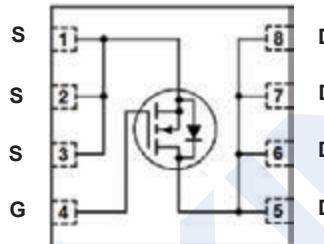
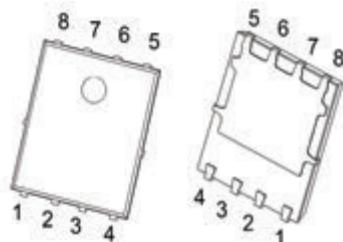
N-Channel MOSFET

2KK5777DFN

■ Features

- $V_{DS} = 30 \text{ V}$
- $I_D (\text{at } V_{GS}=10\text{V}) = 100 \text{ A}$
- $R_{DS(\text{ON})} (\text{at } V_{GS} = 10 \text{ V}) < 3.6 \text{ m}\Omega$
- $R_{DS(\text{ON})} (\text{at } V_{GS} = 4.5 \text{ V}) < 4.7 \text{ m}\Omega$

PDFN5x6-8



■ Absolute Maximum Ratings ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Parameter	Symbol	Rating	Unit
Drain-Source Voltage	V_{DS}	30	V
Gate-Source Voltage	V_{GS}	± 20	
Continuous Drain Current (Note 1)	I_D	100	A
Pulsed Drain Current (Note 2)	I_{DM}	390	
Single Pulse Avalanche Current (Note 2)	I_{AS}	50	A
Single Pulse Avalanche Energy $L = 0.1\text{mH}$ (Note 2)	E_{AS}	125	mJ
Thermal Resistance, Junction- to-Ambient (Note 3, 4)	$R_{\theta JA}$	55	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction- to-Case	$R_{\theta JC}$	2.5	
Power Dissipation (Note 4)	P_D	50	W
		20	
Power Dissipation (Note 5)	P_{DSM}	6.2	
		4	
Junction Temperature	T_J	150	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55 to 150	

Notes:

1. The maximum current rating is package limited.
2. Single pulse width limited by junction temperature $T_J(\text{MAX})=150^\circ\text{C}$.
3. The $R_{\theta JA}$ is the sum of the thermal impedance from junction to case $R_{\theta JC}$ and case to ambient.
4. The power dissipation P_D is based on $T_J(\text{MAX})=150^\circ\text{C}$, using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.
5. The value of $R_{\theta JA}$ is measured with the device mounted on 1in^2 FR-4 board with 2oz. Copper, in a still air environment with $T_A = 25^\circ\text{C}$. The Power dissipation P_{DSM} is based on $R_{\theta JA} t \leq 10\text{s}$ and the maximum allowed junction temperature of 150°C . The value in any given application depends on the user's specific board design.

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■ Electrical Characteristics ($T_J = 25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Test Conditions	Min	Typ	Max	Unit
Static Characteristics						
Drain-Source Breakdown Voltage	BV_{DSS}	$I_D = 250 \mu\text{A}, V_{GS} = 0\text{V}$	30			V
Zero Gate Voltage Drain Current	$I_{DS(0)}$	$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}$			1	μA
		$V_{DS} = 30\text{V}, V_{GS} = 0\text{V}, T_J = 55^\circ\text{C}$			5	
Gate to Source Leakage Current	I_{GSS}	$V_{DS} = 0\text{V}, V_{GS} = \pm 20\text{V}$			± 100	nA
Gate to Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250\mu\text{A}$	1.1		1.9	V
Static Drain-Source On-Resistance	$R_{DS(on)}$	$V_{GS} = 10\text{V}, I_D = 20\text{A}$			3.6	$\text{m}\Omega$
		$V_{GS} = 10\text{V}, I_D = 20\text{A}, T_J = 125^\circ\text{C}$			5.4	
		$V_{GS} = 4.5\text{V}, I_D = 20\text{A}$			4.7	
Forward Transconductance	g_{FS}	$V_{DS} = 5\text{V}, I_D = 20\text{A}$		100		S
Dynamic Characteristics						
Input Capacitance	C_{iss}	$V_{GS} = 0\text{V}, V_{DS} = 15\text{V}, f = 1\text{MHz}$		4080		pF
Output Capacitance	C_{oss}			410		
Reverse Transfer Capacitance	C_{rss}			265		
Gate Resistance	R_g	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, F=1\text{MHz}$	1		3	Ω
Switching Characteristics						
Total Gate Charge (10V)	Q_g	$V_{GS} = 10\text{V}, V_{DS} = 15\text{V}, I_D = 20\text{A}$		63	90	nC
Total Gate Charge (4.5V)				29	40	
Gate Source Charge	Q_{gs}			9		
Gate Drain Charge	Q_{gd}			9.5		
Turn-On Delay Time	$t_{d(on)}$	$V_{GS} = 10\text{V}, V_{DS} = 15\text{V}, R_L = 0.75\Omega, R_{GEN} = 3\Omega$		9		ns
Turn-On Rise Time	t_r			6		
Turn-Off Delay Time	$t_{d(off)}$			52		
Turn-Off Fall Time	t_f			11.5		
Drain-Source Diode Characteristics						
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 20\text{A}, dI/dt = 500\text{A}/\mu\text{s}$		11		ns
Body Diode Reverse Recovery Charge	Q_{rr}			19		nC
Maximum Body-Diode Continuous Current	I_S	(Note 1)			100	A
Diode Forward Voltage	V_{SD}	$V_{GS} = 0\text{V}, I_S = 1\text{A}$		0.7	1	V

Notes:

6. The static characteristics in Figures 1 to 6 are obtained using $<300\mu\text{s}$ pulses, duty cycle 0.5% max.
7. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_J(\text{MAX})=150^\circ\text{C}$. The SOA curve provides a single pulse rating.

■ Marking

Marking	K5777 KC***
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■ Typical Characteristics

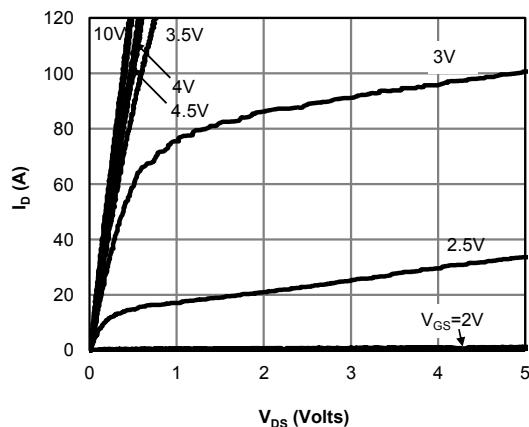


Figure 1: On-Region Characteristics (Note 6)

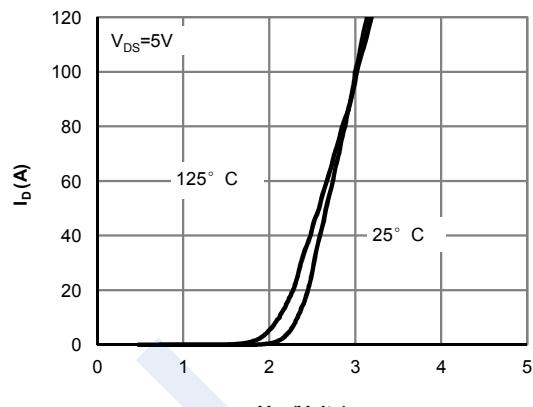


Figure 2: Transfer Characteristics (Note 6)

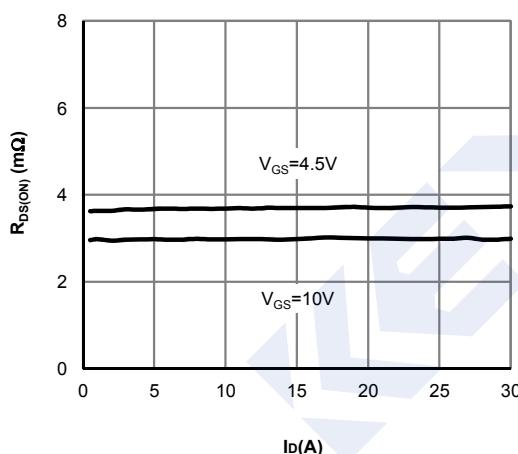


Figure 3: On-Resistance vs. Current and Gate Voltage (Note 6)

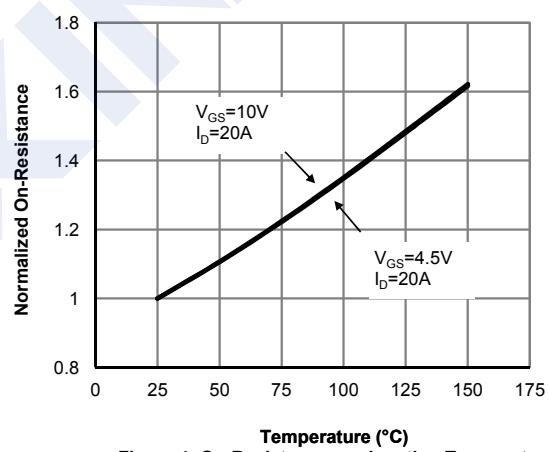


Figure 4: On-Resistance vs. Junction Temperature (Note 6)

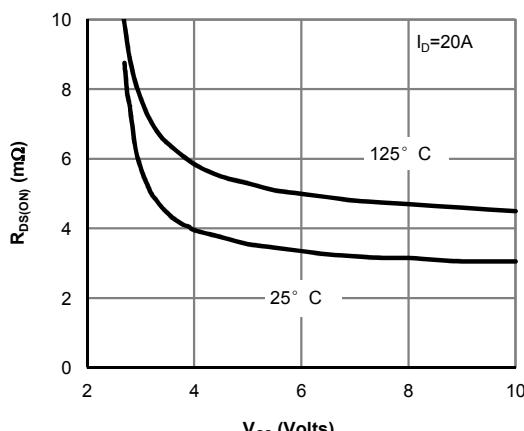


Figure 5: On-Resistance vs. Gate-Source Voltage (Note 6)

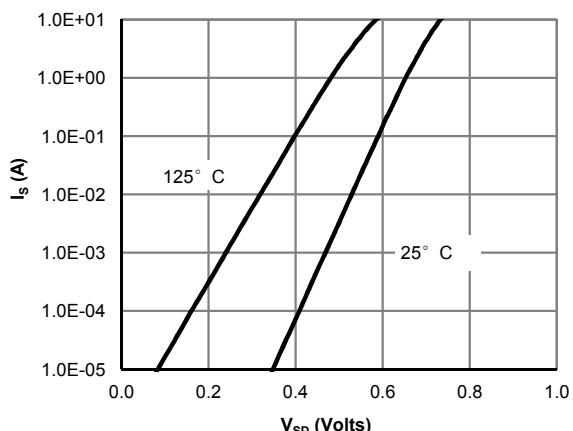


Figure 6: Body-Diode Characteristics (Note 6)

N-Channel MOSFET

2KK5777DFN

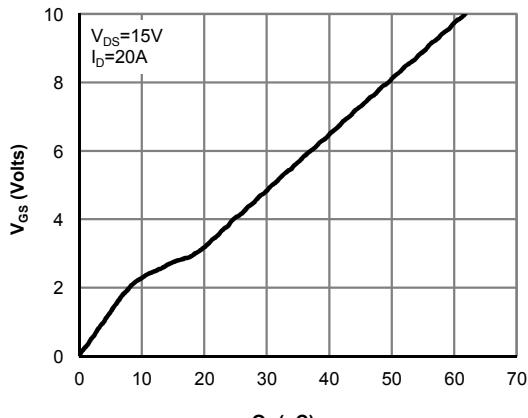


Figure 7: Gate-Charge Characteristics

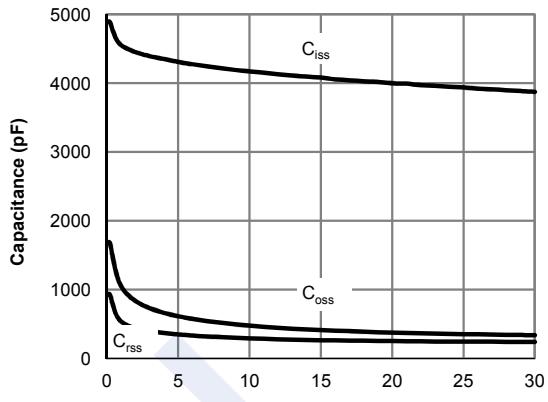


Figure 8: Capacitance Characteristics

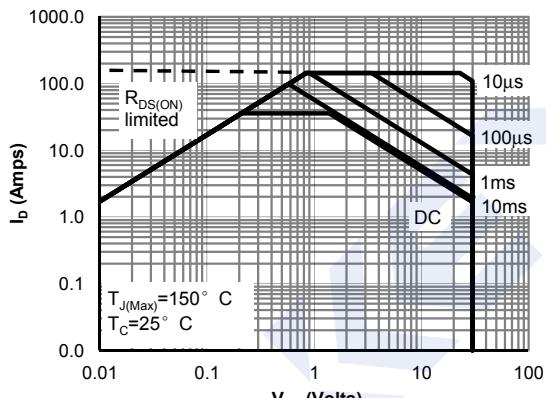


Figure 9: Maximum Forward Biased Safe Operating Area (Note 7)

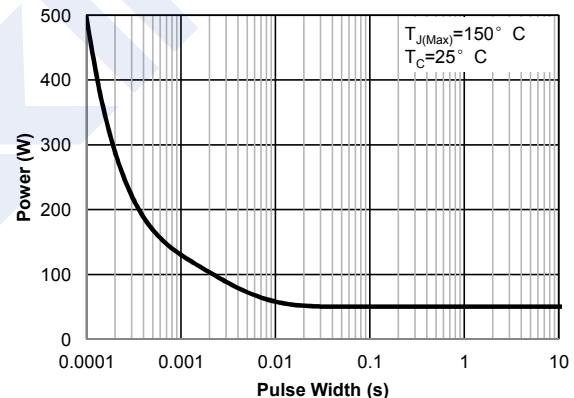


Figure 10: Single Pulse Power Rating Junction-to-Case (Note 7)

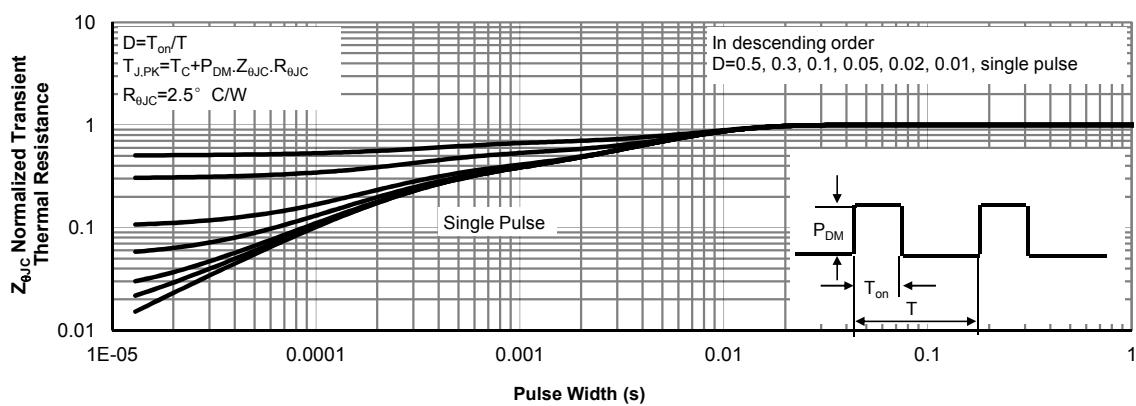
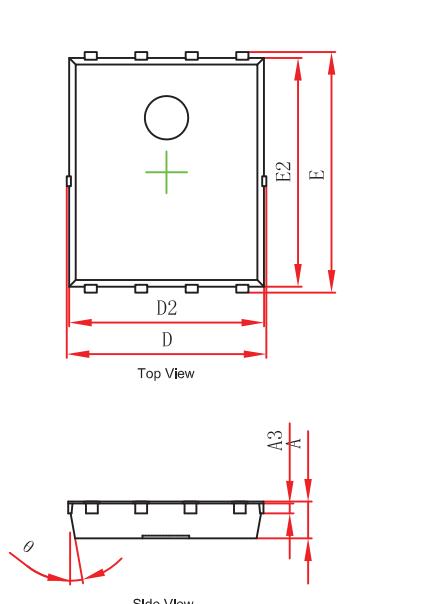
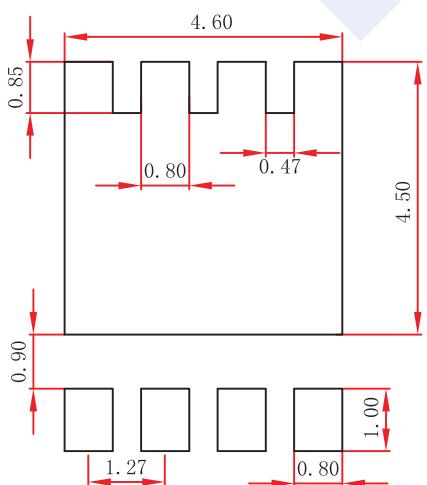


Figure 11: Normalized Maximum Transient Thermal Impedance (Note 7)

N-Channel MOSFET**2KK5777DFN****■ PDFN5x6-8 Package Outline Dimensions**

Bottom View

Symbol	Dimensions In Millimeters		Dimensions In Inches	
	Min.	Max.	Min.	Max.
A	0.900	1.000	0.035	0.039
A3	0.254REF.	0.254REF.	0.010REF.	0.010REF.
D	4.944	5.096	0.195	0.201
E	5.974	6.126	0.235	0.241
D1	3.910	4.110	0.154	0.162
E1	3.375	3.575	0.133	0.141
D2	4.824	4.976	0.190	0.196
E2	5.674	5.826	0.223	0.229
k	1.190	1.390	0.047	0.055
b	0.350	0.450	0.014	0.018
e	0.559	0.711	0.022	0.028
L	0.424	0.576	0.017	0.023
L1	0.574	0.726	0.023	0.029
H	0.574	0.726	0.023	0.029
θ	10°	12°	10°	12°

■ PDFN5x6-8 Suggested Pad Layout**Note:**

1. Controlling dimension: in millimeters.
2. General tolerance: $\pm 0.05\text{mm}$.
3. The pad layout is for reference purposes only.